

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/583,613	SCHMIDT ET AL.	
	Examiner	Art Unit	Page 1 of 1
	Alex W. Mok	2834	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,896,064	01-1990	Taiani, Patrick M.	310/104
*	B	US-4,146,805	03-1979	Fehr et al.	310/104
*	C	US-3,936,683	02-1976	Walker, Alan John	310/103
*	D	US-4,396,849	08-1983	Taiani, Patrick M.	310/92
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 255723 A	02-1988	European Patent	BIENIEK et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.